TOSHIBA 2SC2395

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 2 3 9 5

2~30MHz SSB LINEAR POWER AMPLIFIER APPLICATIONS (LOW SUPPLY VOLTAGE USE)

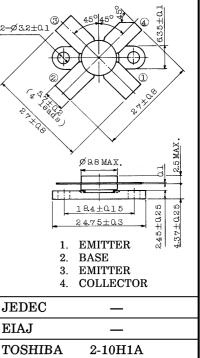
Specified 12.5V, 28MHz Characteristics

Output Power : Po=10WpEp (Min.)
 Power Gain : Gp=17dB (Min.)
 Collector Efficiency : ηC=35% (Min.)
 Intermodulation Distortion : IMD=-30dB (Max.)

MAXIMUM RATINGS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	40	V
Collector-Emitter Voltage	v_{CES}	40	V
Collector-Emitter Voltage	V_{CEO}	18	V
Emitter-Base Voltage	V_{EBO}	4	V
Collector Current	$I_{\mathbf{C}}$	5	A
Collector Power Dissipation	$P_{\mathbf{C}}$	40	W
Junction Temperature	T_{j}	175	°C
Storage Temperature Range	$ m T_{stg}$	-65~175	°C

Unit in mm



Weight: 4.0g

ELECTRICAL CHARACTERISTICS (Tc = 25°C)

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CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector-Emitter Breakdown Voltage	V (BR) CEO	$I_{C}=10mA, I_{B}=0$	18	_	_	V
Collector-Emitter Breakdown Voltage	V _(BR) CES	$I_{C}=50$ mA, $V_{EB}=0$	40	_	_	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	$I_E=1$ mA, $I_C=0$	4	_	_	V
DC Current Gain	$h_{ ext{FE}}$	V _{CE} =5V, I _C =1A *	20	_	_	
Transition Frequency	$\mathbf{f_{T}}$	$V_{\text{CE}} = 5V, I_{\text{C}} = 1A$	_	200	_	MHz
Collector Output Capacitance	Cob	$V_{CB} = 12.5V, I_{E} = 0$ f=1MHz	_	_	150	pF
Power Gain	$G_{ m p}$	$V_{CC} = 12.5V, f_1 = 28.000$	17.0	_	_	dB
Input Power	Pi	MHz, $f_2 = 28.001 \text{MHz}$	_	_	0.2	W_{PEP}
Collector Efficiency	$\eta_{\mathbf{C}}$	I _{idle} =50mA	35	45	_	%
Intermodulation Distortion	IMD	$Po = 10W_{PEP}(Fig.)$	_	_	-30	dB
Series Equivalent Input Impedance	Z _{in}	V _{CC} =12.5V, f ₁ =28.000 MHz, f ₂ =28.001MHz	_	1.5 -j1.0	_	Ω
Series Equivalent Output Impedance	Z _{out}	Po=10WpEp	_	6.5 -j2.0	_	Ω

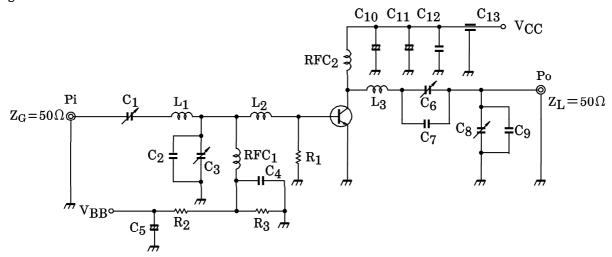
^{*} Pulse Test: Pulse Width \leq 100 μ s, Duty Cycle \leq 3% CAUTION

Beryllia Ceramic is used in this product. The dust or vapor can be dangerous to humans. Do not break, cut, crush or dissolve chemically. Dispose of this product properly according to law. Do not intermingle with normal industrial or domestic waste.

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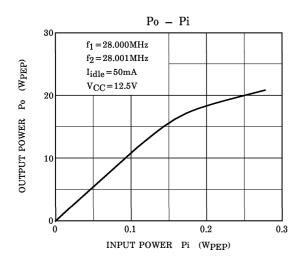
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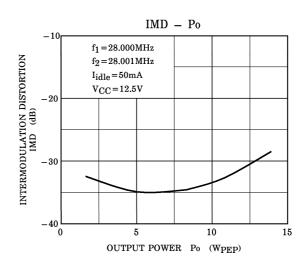
Fig. Pi TEST CIRCUIT



 C_{13} : 1000pF

(FEED THROUGH)





CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.

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